

Applicant: Ippei Shake et al.

Confirmation No.: 4422

Serial No.: 10/585,532

Att'y Docket No.: 14321.87

Filing Date: July 10, 2006

Art Unit: 2633

For: OPTICAL SIGNAL QUALITY MONITORING CIRCUIT AND OPTICAL SIGNAL  
QUALITY MONITORING METHODSUPPLEMENTAL INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANTU.S. Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
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Foreign Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Publication Date</u>	<u>Country or Patent Office</u>	<u>Translation</u>
/D.T./ 1	09-233030	09/05/1997	Japan	No
/D.T./ 2	10-240297	09/11/1998	Japan	No
/D.T./ 3	2000-078084	03/14/2000	Japan	No
/D.T./ 4	2002-247117	08/30/2002	Japan	No
/D.T./ 5	2003-209522	07/25/2003	Japan	No

Other Documents

(including author, title, pertinent pages, etc.)

Examiner  
Initial\*

/D.T./ 6      Ippei Shake et al., *Simple Q Factor Monitoring for BER Estimation Using Opened Eye Diagrams Captured by High-Speed Asynchronous Electrooptical Sampling*, IEEE Photonics Technology Letters, Vol. 15, No. 4, April 2003, pp. 620-622.

Examiner: /Dzung Tran/ Date Considered:

06/18/2009

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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QUALITY MONITORING METHOD**References Cited by Applicants**

While the filing of Information Disclosure Statements is voluntary, the procedure is governed by the guidelines of Section 609 of the Manual of Patent Examining Procedure and 37 C.F.R. §§ 1.97 and 1.98. To be considered a proper Information Disclosure Statement, Form PTO-1449 shall be accompanied by a copy of each listed patent or publication or other item of information and a translation of the pertinent portions of foreign documents (if an existing translation is readily available to the applicant), an explanation of relevance of each reference not in the English language, and should be submitted in a timely manner as set out in MPEP Sec. 609.

Examiners will consider all citations submitted in conformance with 37 C.F.R. § 1.98 and MPEP Sec. 609 and place their initials adjacent the citations in the spaces provided on this form. Examiners will also initial citations not in conformance with the guidelines which may have been considered. A reference may be considered by the Examiner for any reason whether or not the citation is in full conformance with the guidelines. A line will be drawn through a citation if it is not in conformance with the guidelines AND has not been considered. A copy of the submitted form, as reviewed by the Examiner, will be returned to the applicant with the next communication. The original of the form will be entered into the application file.

Each citation initialed by the Examiner will be printed on the issued patent in the same manner as references cited by the Examiner on Form PTO-892.

The reference designations "A1," "A2," etc. (referring to Applicant's reference 1, Applicant's reference 2, etc.) will be used by the Examiner in the same manner as Examiner's reference designations "A," "B," "C," etc. on Office Action Form PTO-1142.

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/Dzung Tran/

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